KNN Find k examples $\{\mathbf{x}^{(i)}, t^{(i)}\}$ closest to the test instance \mathbf{x} and then output majority $\arg\max_{t^z} \sum_{r=1}^k \delta(t^{(z)}, t^{(r)})$. Define $\delta(a, b) = \sum_{t=1}^k \delta(t^{(z)}, t^{(t)})$. 1 if a = b, 0 otw. Choice of k: Rule is $k < \sqrt{n}$, small k may overfit, while large may under-fit. Curse of Dim: In high dimensions, "most" points are approximately the same distance. Computation Cost: 0 (minimal) at training/ no learning involved. Query time find N distances in D dimension $\mathcal{O}(ND)$ and $\mathcal{O}(N\log N)$ sorting time.

Entropy $H(X) = -\mathbb{E}_{X \sim p} [\log_2 p(X)] = -\sum_{x \in X} p(x) \log_2 p(x)$ Multi-class: $H(X,Y) = -\sum_{x \in X} \sum_{y \in Y} p(x,y) \log_2 p(x,y)$ Properties: H is non-negative, $H(Y|X) \leq H(Y)$, $X \perp Y \implies H(Y|X) = H(Y)$, H(Y|Y) = 0, and H(X,Y) = H(X|Y) + H(Y) = 0H(Y|X) + H(X)

Expected Conditional Entropy $H(Y|X) = \mathbb{E}_{X \sim p(x)}[H(Y|X)] = \sum_{x \in X} p(x)H(Y|X = x) = -\sum_{x \in X} \sum_{y \in Y} p(x,y)\log_2 p(y|x) = -\mathbb{E}_{(X,Y) \sim p(x,y)}\left[\log_2 p(Y|X)\right]$ Information Gain IG(Y|X) = H(Y) - H(Y|X)

Bias Variance Decomposition Using the square error loss $L(y,t) = \frac{1}{2}(y-t)^2$, Bias ($\uparrow \Longrightarrow$ under-fitting): How close is our classifier to true target. Variance ($\uparrow \Longrightarrow$ overfitting): How widely dispersed are out predictions as we generate new datasets

$$\mathbb{E}_{\mathbf{x},\mathcal{D}}\left[\left(h_{\mathcal{D}}(\mathbf{x})-t\right)^{2}\right] = \mathbb{E}_{\mathbf{x},\mathcal{D}}\left[\left(h_{\mathcal{D}}(\mathbf{x})-\mathbb{E}_{\mathcal{D}}\left[h_{\mathcal{D}}(\mathbf{x})\right]+\mathbb{E}_{\mathcal{D}}\left[h_{\mathcal{D}}(\mathbf{x})\right]-t\right)^{2}\right]$$

$$= \mathbb{E}_{\mathbf{x},\mathcal{D}}\left[\left(h_{\mathcal{D}}(\mathbf{x})-\mathbb{E}_{\mathcal{D}}\left[h_{\mathcal{D}}(\mathbf{x})\right]\right)^{2}+\left(\mathbb{E}_{\mathcal{D}}\left[h_{\mathcal{D}}(\mathbf{x})\right]-t\right)^{2}+2\left(h_{\mathcal{D}}(\mathbf{x})-\mathbb{E}_{\mathcal{D}}\left[h_{\mathcal{D}}(\mathbf{x})\right]\right)\left(\mathbb{E}_{\mathcal{D}}\left[h_{\mathcal{D}}(\mathbf{x})\right]-t\right)\right]$$

$$= \underbrace{\mathbb{E}_{\mathbf{x},\mathcal{D}}\left[\left(h_{\mathcal{D}}(\mathbf{x})-\mathbb{E}_{\mathcal{D}}\left[h_{\mathcal{D}}(\mathbf{x})\right]\right)^{2}\right]}_{\text{variance}} + \underbrace{\mathbb{E}_{\mathbf{x}}\left[\left(\mathbb{E}_{\mathcal{D}}\left[h_{\mathcal{D}}(\mathbf{x})\right]-t\right)^{2}\right]}_{\text{bias}}$$

Bagging with Generating Distribution Suppose we could sample m independent training sets $\{\mathcal{D}_i\}_{i=1}^m$ from $p_{dataset}$. Learn $h_i := h_{\mathcal{D}_i}$ and out final predictor is $h = 1/m \sum_{i=1}^m h_i$. Bias Unchanged: $\mathbb{E}_{\mathcal{D}_1, \dots, \mathcal{D}_m} \stackrel{iid}{\sim} p_{dataset} [h(\mathbf{x})] = \frac{1}{m} \sum_{i=1}^m \mathbb{E}_{\mathcal{D}_i \sim p_{dataset}} [h_i(\mathbf{x})] = \mathbb{E}_{\mathcal{D} \sim p_{dataset}} [h_{\mathcal{D}}(\mathbf{x})]$ Variance Reduced: $\operatorname{Var}_{\mathcal{D}_1, \dots, \mathcal{D}_m} [h(\mathbf{x})] = \frac{1}{m^2} \sum_{i=1}^m \operatorname{Var} [h_i(\mathbf{x})] = \frac{1}{m} \operatorname{Var} [h_{\mathcal{D}}(\mathbf{x})]$

Bootstrap Aggregation Take a single dataset \mathcal{D} with n sample and generate m new datasets, each by sampling n training examples from \mathcal{D} , with replacement. We then the average the predictions. We have the reduction in variance to be $\operatorname{Var}\left(\frac{1}{m}\sum_{i=1}^{m}h_{i}(\mathbf{x})\right)=1$ $\frac{1}{m}(1-\rho)\sigma^2 + \rho\sigma^2$

Random Forest Upon bootstrap aggregation, for each bag we choose a random set of features to make the trees grow on (decorrelates predictions, lower ρ).

Bayes Optimality
$$\mathbb{E}_{\mathbf{x},\mathcal{D},t|\mathbf{x}}\left[\left(h_{\mathcal{D}}(\mathbf{x})-t\right)^{2}\right] = \underbrace{\mathbb{E}_{\mathbf{x}}\left[\left(\mathbb{E}_{\mathcal{D}}\left[h_{\mathcal{D}}(\mathbf{x})\right]-y_{*}(\mathbf{x})\right)^{2}\right]}_{\text{bias}} + \underbrace{\mathbb{E}_{\mathbf{x},\mathcal{D}}\left[\left(h_{\mathcal{D}}(\mathbf{x})-\mathbb{E}_{\mathcal{D}}\left[h_{\mathcal{D}}(\mathbf{x})\right]\right)^{2}\right]}_{\text{variance}} + \underbrace{\mathbb{E}_{\mathbf{x}}\left[\text{Var}[t|\mathbf{x}]\right]}_{\text{Bayes}}$$

Feature Mapping Some time we want fit a polynomial curve, we can do this using a feature map $y = \mathbf{w}^{\top} \psi(x)$ where $\psi(x) = \mathbf{w}^{\top} \psi(x)$ $[1, x, x^2, \ldots]^{\perp}$. In general the feature map could be anything.

Ridge Regression $\mathbf{w}_{\lambda}^{Ridge} = \operatorname{argmin} \mathcal{J}_{reg}(\mathbf{w}) = \operatorname{argmin} \frac{1}{2} \|\mathbf{X}\mathbf{w} - \mathbf{t}\|_{2}^{2} + \frac{\lambda}{2} \|\mathbf{w}\|_{2}^{2} = \left(\mathbf{X}^{T}\mathbf{X} + \lambda \mathbf{I}\right)^{-1} \mathbf{X}^{T}\mathbf{t}$ When $\lambda = 0$ this is just OLS.

- Gradient Descent Consider the some cost function \mathcal{J} and we want to optimize it.

 GD: $\mathbf{w} \leftarrow \mathbf{w} \alpha \frac{\partial \mathcal{J}}{\partial \mathbf{w}}$; GD $\mathbf{w}/$ Reg $\mathbf{w} \leftarrow \mathbf{w} \alpha \left(\frac{\partial \mathcal{J}}{\partial \mathbf{w}} + \lambda \frac{\partial \mathcal{R}}{\partial \mathbf{w}}\right) = (1 \alpha \lambda)\mathbf{w} \alpha \frac{\partial \mathcal{J}}{\partial \mathbf{w}}$ mSGD: Choose mini batch $\mathcal{M} \subset \{1, ..., N\}$ and update $\mathbf{w} \leftarrow \mathbf{w} \frac{\alpha}{|\mathcal{M}|} \sum_{i=1}^{|\mathcal{M}|} \frac{\partial \mathcal{L}^{(i)}}{\partial \mathbf{w}}$ Reasonable size would be $|\mathcal{M}| \approx 100$ SGD: Choose i at uniform; $\mathbf{w} \leftarrow \mathbf{w} \alpha \frac{\partial \mathcal{L}^{(i)}}{\partial \mathbf{w}}$; Pro//Cons: Progress w/o seeing all data//High Variance & Not efficiently vectorized

Cross Entropy Loss $\mathcal{L}_{CE} = -t \log y - (1-t) \log(1-y)$ Logistic CE $\mathcal{L}_{LCE}(z,t) = \mathcal{L}_{CE}(\sigma(z),t) = t \log(1+e^{-z}) + (1-t) \log(1+e^{z})$

Multi-class Classification

- Softmax Function Natural generalization of logistic func: $y_k = \operatorname{softmax}(z_1, \dots, z_K)_k = \frac{e^{z_k}}{\sum_{k'} e^{z_{k'}}}$; iuputs z_k are called logits.
- CE Loss, Vectorized $\mathcal{L}_{CE}(\mathbf{y}, \mathbf{t}) = -\sum_{k=1}^{K} t_k \log y_k = -\mathbf{t}^{\top}(\log \mathbf{y})$ where the log is applied elementwise.
- Softmax Regression $\mathbf{z} = \mathbf{W}\mathbf{x} + \mathbf{b}$, $\mathbf{y} = \operatorname{softmax}(\mathbf{z})$, and $\mathcal{L}_{CE} = -\mathbf{t}^{\top}(\log \mathbf{y})$; GD Updates is $\mathbf{w}_k \leftarrow \mathbf{w}_k \alpha \frac{1}{N} \sum_{i=1}^{N} \left(y_k^{(i)} t_k^{(i)}\right) \mathbf{x}^{(i)}$ where \mathbf{w}_k means the k-th row of \mathbf{W}

Activation Functions Identity y = z ReLU $y = \max(0, z)$ Soft ReLU $y = \log(1 + e^z)$ Thresholding y = 1 if z > 0 else 0. Logistic $y = \frac{1}{1+e^{-z}} \tanh y = \frac{e^z - e^{-z}}{e^z + e^{-z}}$

Multilayer Perceptron

- Modularity of Layers $\mathbf{h}^{(1)} = f^{(1)}(\mathbf{x}) = \phi\left(\mathbf{W}^{(1)}\mathbf{x} + \mathbf{b}^{(1)}\right), \ \mathbf{h}^{(2)} = f^{(2)}\left(\mathbf{h}^{(1)}\right) = \phi\left(\mathbf{W}^{(2)}\mathbf{h}^{(1)} + \mathbf{b}^{(2)}\right), \dots, \ \mathbf{y} = f^{(L)}\left(\mathbf{h}^{(L-1)}\right) = \mathbf{b}^{(L)}\left(\mathbf{h}^{(L-1)}\right) = \mathbf{b}^{(L)}\left(\mathbf{h}^{(L)}\right) = \mathbf{b}^{(L)}\left(\mathbf{h}$
- Choice of Last Layer Activation Func Regression: $\mathbf{y} = f^{(L)} \left(\mathbf{h}^{(L-1)} \right) = \left(\mathbf{w}^{(L)} \right)^T \mathbf{h}^{(L-1)} + b^{(L)}$; Binary Classification: $\mathbf{y} = f^{(L)} \left(\mathbf{h}^{(L-1)} \right) = \sigma \left(\left(\mathbf{w}^{(L)} \right)^T \mathbf{h}^{(L-1)} + b^{(L)} \right)$
- Back Propagation Suppose \mathcal{L} what I want to optimize, then for some variable w that we want to optimize w.r.t., $\frac{\partial \mathcal{L}}{\partial \mathbf{w}} =: \overline{\mathbf{w}}$
- Back Prop Cost Forward: one add-multiplicity operation per weight; Backward: two add-multiplicity operations per weight ⇒ the Backward pass is about as expensive as two Forward passes. (cost is linear in # of layers, quadratic in # of units per layer)

Statistic on Samples

- Sample Mean $\hat{\boldsymbol{\mu}} = \frac{1}{N} \sum_{i=1}^{N} \mathbf{x}^{(i)}$. $\hat{\boldsymbol{\mu}}$ roughly quantifies where your data is located in space Sample Cov $\hat{\boldsymbol{\Sigma}} = \frac{1}{N} \sum_{i=1}^{N} \left(\mathbf{x}^{(i)} \hat{\boldsymbol{\mu}} \right) \left(\mathbf{x}^{(i)} \hat{\boldsymbol{\mu}} \right)^{\top}$ quantifies the shape of spread of the data

Euclidean projection Let S denote the subspace with dim = k that is spanned by the basis $\{\mathbf{u}_1, ..., \mathbf{u}_K\} \subseteq \mathbb{R}^D$. Then,

- Any vector $\mathbf{y} \in \mathcal{S}$ could be represented as $\mathbf{y} = \sum_{i=1}^{K} z_i \mathbf{u}_i$, for some $z_1, ..., z_k \in \mathbb{R}$ The projection of \mathbf{x} onto \mathcal{S} is given as $\operatorname{Proj}_{\mathcal{S}}(\mathbf{x}) = \sum_{i=1}^{K} (\mathbf{x}^{\top} \mathbf{u}_i) \mathbf{u}_i = \sum_{i=1}^{K} z_i \mathbf{u}_i$

Principle Component Analysis - Projection onto Subspace

- Let $\{\mathbf{u}_k\}_{k=1}^K$ be an orthonormal basis of the subspace \mathcal{S} .
- Define U to be a matrix with columns {u_k}^K_{k=1} then z = U^T(x µ̂). Here the z is called the code vector
 Also, x̃ = µ̂ + Uz = µ̂ + UU^T(x µ̂) is called the reconstruction of x
 Note: UU^T is the projector matrix and U^TU = I is the identity matrix.

- \mathbf{x} and $\tilde{\mathbf{x}}$ are both in \mathbb{R}^D while $\tilde{\mathbf{x}}$ lives in a low dimensional subspace in \mathbb{R}^D . The code vector \mathbf{x} is in \mathbb{R}^K , and is the low dim representation of the vector \mathbf{x}

PCA - Learning Subspace

- Criteria I: Minimize the reconstruction error: Find vectors in a subspace that are closest to data points, $\min_{\mathbf{U}} \frac{1}{N} \sum_{i=1}^{N} \left\| \mathbf{x}^{(i)} \tilde{\mathbf{x}}^{(i)} \right\|^2$
- Criteria II: Maximize the variance of reconstructions: Find subspaces where data has the most variability, $\max_{\mathbf{U}} \frac{1}{N} \sum_{i} \|\tilde{\mathbf{x}}^{(i)} \hat{\boldsymbol{\mu}}\|^2$ Proof: Criteria I = Criteria II; It suffices to show that $\frac{1}{N} \sum_{i=1}^{N} \|\mathbf{x}^{(i)} \tilde{\mathbf{x}}^{(i)}\|^2 = \text{const} \frac{1}{N} \sum_{i} \|\tilde{\mathbf{x}}^{(i)} \hat{\boldsymbol{\mu}}\|^2$

Work Flow of EM and GGM

- Step 0; Assume (1). Pick a cluster (with probability π_k) and (2). sample from it using the parameters μ_k, Σ_k . (Some gaussian distribution)
- Step 1; The log-likelihood is $\log P(X|\pi, \mu_k, \Sigma_k) = \sum_{i=1}^N \log \sum_{k=1}^K \pi_k N(X_n|\mu_k, \Sigma_k)$
- Step 2; Optimize via EM
- Step 2.1 Compute responsibilities (E)
- Step 2.2 Maximize (M)

$$\mu_k = \frac{1}{N_k} \sum_k$$

• Notice that Generative models are called "generative" because they try to learn the underlying distribution, while the discriminative analysis procedures (eg NN) are trying to simply map data.